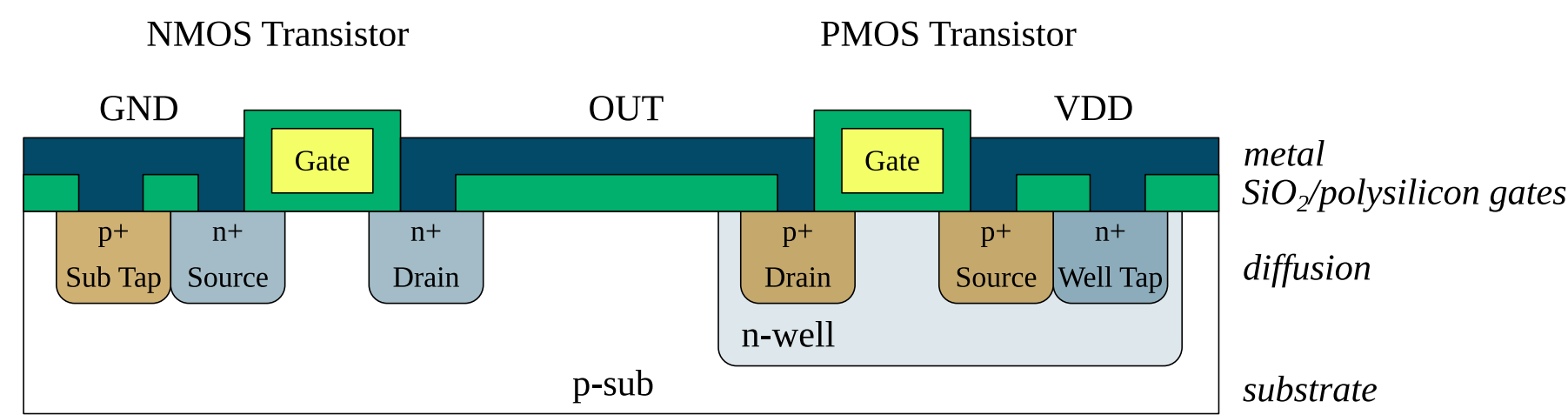


Motivation

- Security of many digital devices strongly depends on a secret value stored in them
- New attacks are invented continuously
 - it is important to analyze even potential threats to mitigate device vulnerability during its lifetime
 - yet unexplored properties of CMOS may lead to security threats

Photoelectric Laser Stimulation



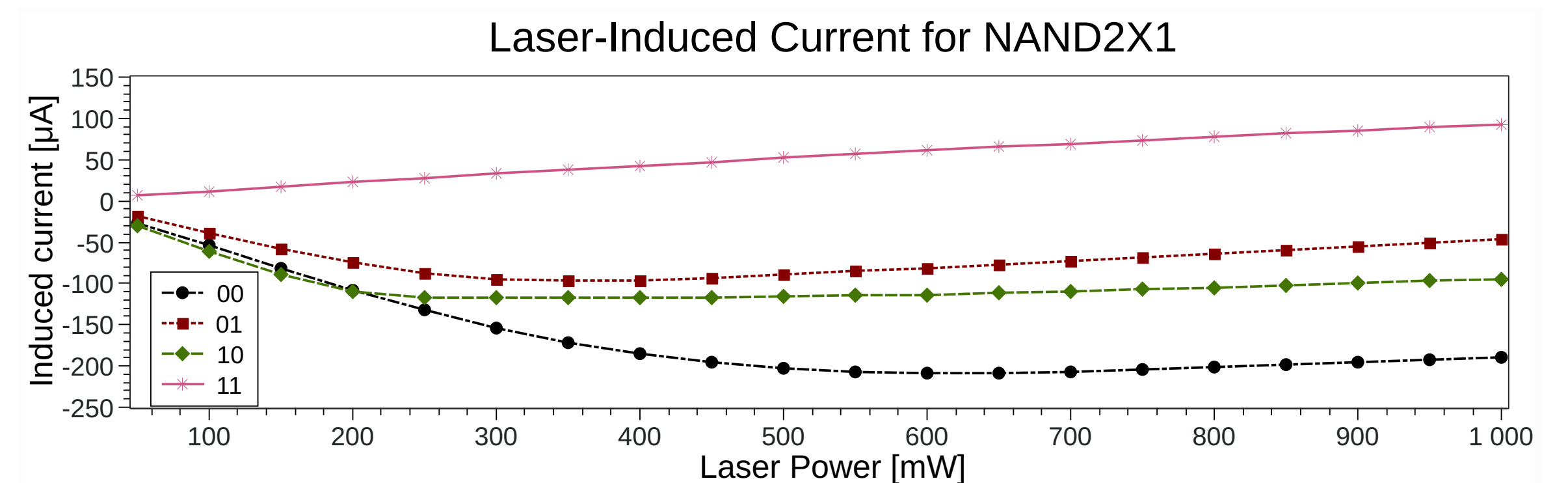
CMOS cross-section – the PN junctions

The laser beam passing through silicon creates electron-hole pairs along its path (as a result of energy absorption). The *Optical Beam Induced Current (OBIC)* is generated along PN junctions.

Contribution

- Bělohoubek, J.; Fišer, P.; Schmidt, J.: *CMOS Illumination Discloses Processed Data*. In: *Proceedings of the 22nd Euromicro Conference on Digital Systems Design*. Los Alamitos, CA: IEEE Computer Soc., 2019. p. 381-388. ISBN 978-1-7281-2862-7.
 - Laser illumination of CMOS logic leads to data-dependent power trace imprint
- Bělohoubek, J.; Fišer, P.; Schmidt, J.: “Using Voters May Lead to Secret Leakage”. In: *22nd International Symposium on Design and Diagnostics of Electronic Circuits and Systems (DDECS 2019)*. Cluj-Napoca, Romania, April 24-26, 2019.
 - Laser illumination of CMOS conventional majority voter – in connection with SPA – allows to read logic values at the voter inputs – “Majority Voter as the Amplifier”

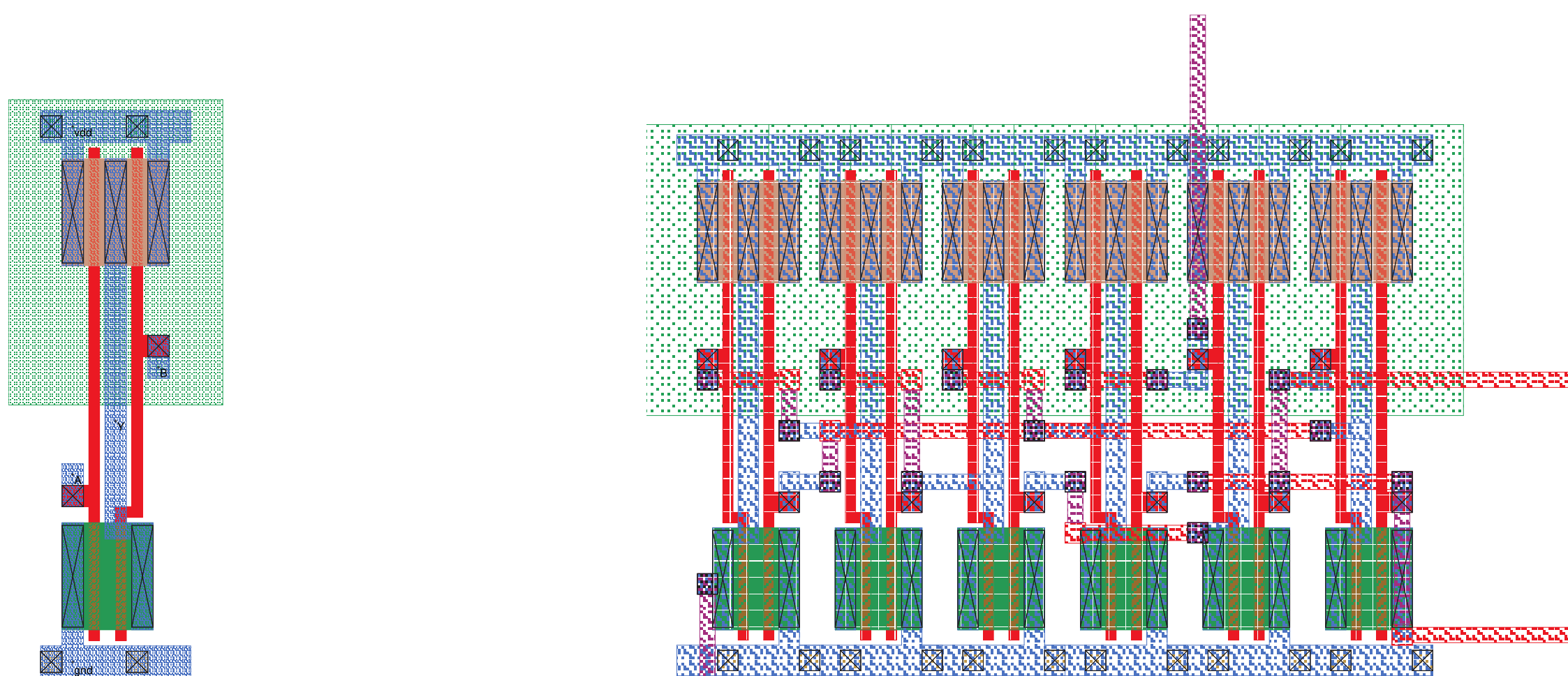
Data-Dependent Power Trace Imprint



Laser Power and Input Data Dependency:

- all input values can be distinguished clearly (in the power trace) for the two-input NAND gate
- data-dependent part of the induced photocurrent depends on laser power

Experiment Setup and Replicability



NAND2X1 gate layout produced by Magic; Area: 10 x 3 μm in TSMC 180nm technology

Voter layout produced by Magic Area: 10 x 18 μm → easy to target by a laser beam

- SPICE models for *pulsed photoelectric laser stimulation (PLS)* of NMOS/PMOS based on work of Sarafianos et al.
 - Available at the DDD Research Group website and on GitHub
 - <https://ddd.fit.cvut.cz/prj/CMOS-PLS/>
 - <https://github.com/DDD-FIT-CTU/CMOS-PLS/>
- The open tools: *digital synthesis flow* – Qflow, Magic, ngSPICE
- TSMC 180nm open standard cell library provided by Oklahoma State University

Proposed Attacks

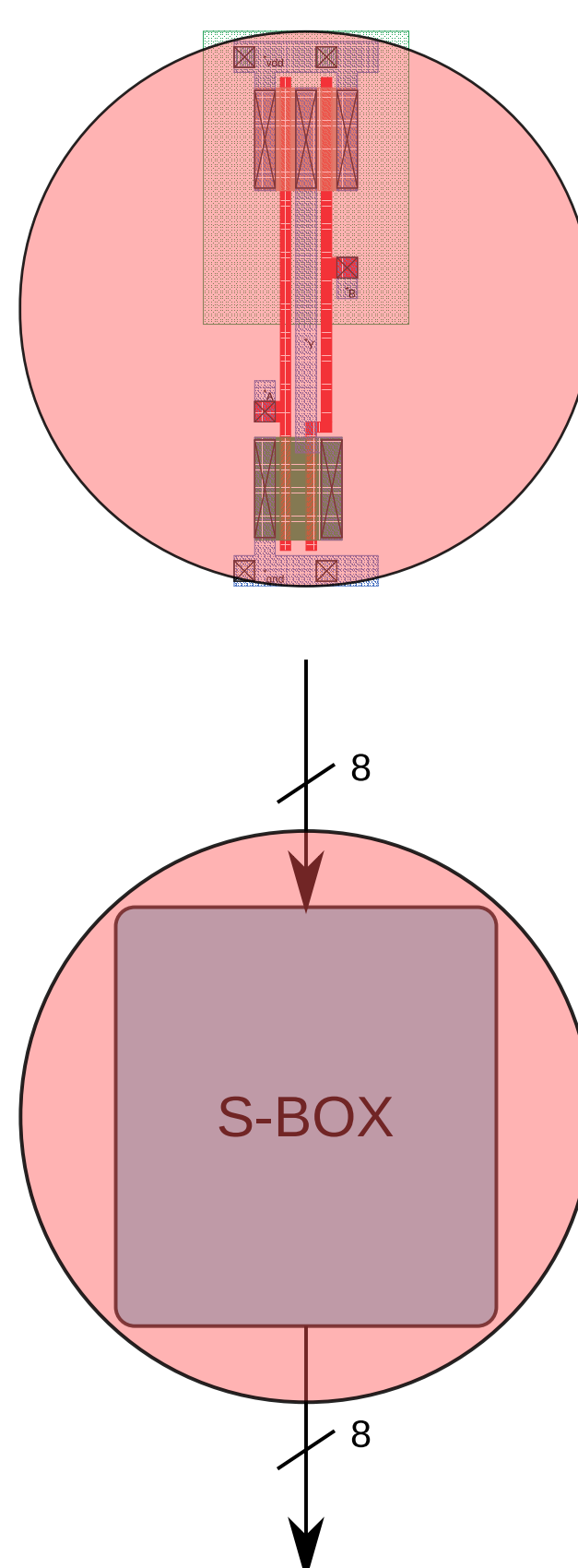
Proposed attacks are based on static power measurement:

- Static power is modulated by laser beam
- Simple Power Analysis (SPA) is employed

Template attacks are feasible:

- Monte Carlo SPICE simulations have shown, that the inter-die differences in laser-induced photocurrent are not significant
 - Reading individual bits by the **single gate illumination** should be possible when gate sizes are reasonable with respect to the laser beam spot size
 - For bigger circuits (e.g. AES S-BOX), a **circuit power model under illumination** may be composed (by measurements) and measured data from the device-under-attack may be correlated with the power model

Attack scenarios feasibility must be confirmed by measurement!



Future Work

- Measurements on real devices
- Comparison of the proposed Attack with State-of-the-art attacks (DPA)
- Influence of the logic surrounding the illuminated logic should be investigated
- Cocktail Effect Research – decreasing the entropy of processed data by the modulated static power analysis (for bigger circuits)

Conclusions

- The static power of CMOS logic under PLS is correlated with processed data
 - we identified the potential threat endangering the security of CMOS circuits in general and majority voters in particular**
- Our work is completely replicable: open tools were used, developed models and related resources were released under BSD-like license

If a CMOS circuit is illuminated (by a laser beam), while the activity of the circuit is suppressed (stable clock and inputs), the **laser-modulated static power** of the *circuit under attack* is **strongly influenced by logic values** at the circuit inputs.

The authors acknowledge the support of the OP VVV MEYS funded project CZ.02.1.01/0.0/0.0/16_019/0000765 “Research Center for Informatics” and the CTU grant SGS17/213/OHK3/3T/18.